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EECS251B : Advanced Digital Circuits and Systems

Lecture 14 – Latches

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AMD Allies with Ranovus on Data Center Photonics Module
March 6, 2022, EETimes

The co-packaged optical (CPO) demonstration system built by Xilinx and Ranovus. It incorporates the former's Versal ACAP with the latter's Odin Analog-Drive CPO 2.0. (Source: Ranovus)



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Recap

- Flip-flop-based (edge-triggered) timing dominates today
- Latch-based timing can increase performance, but needs extra care
- There is also asynchronous design

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Design for Performance

Latch Design

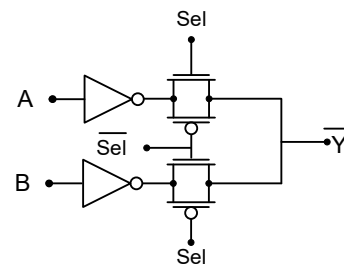
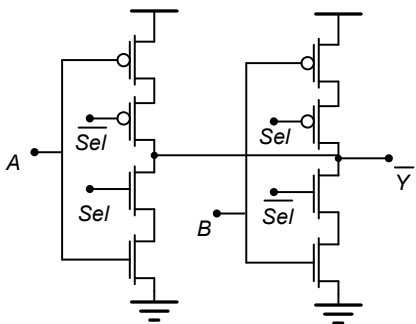
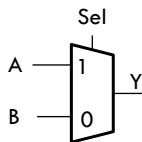
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Review: MUX

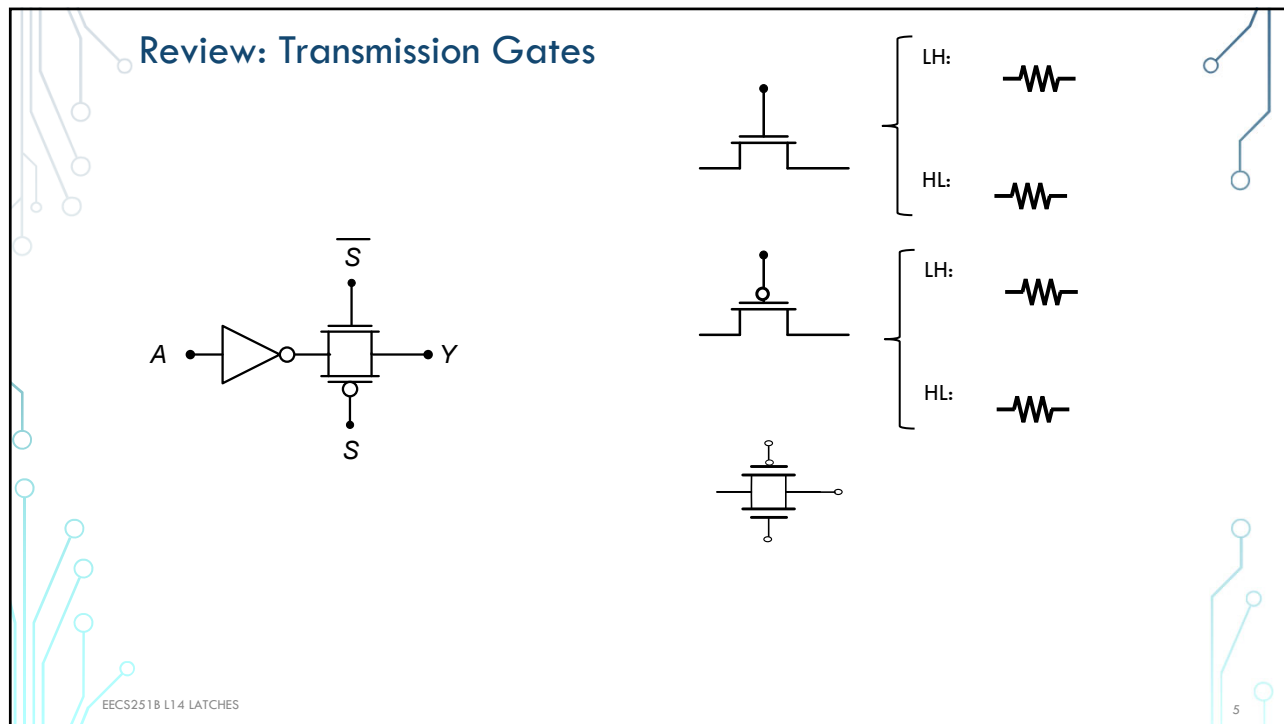
- 2-input MUX



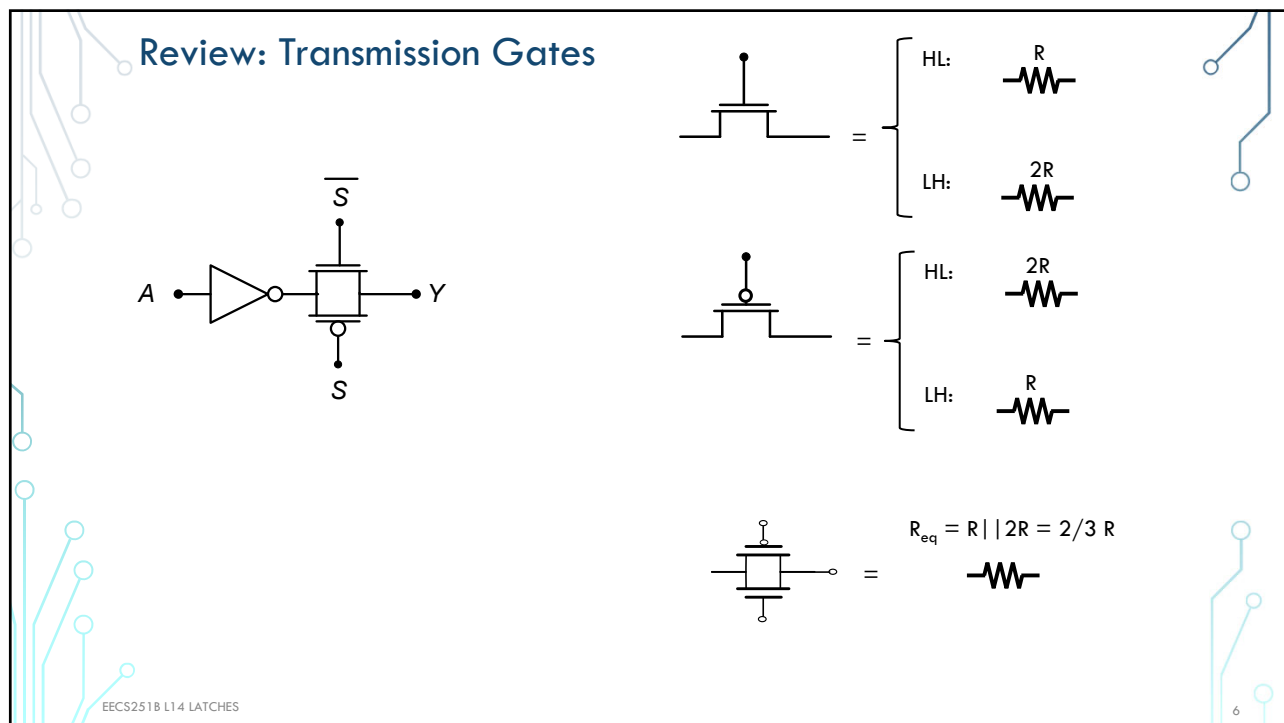
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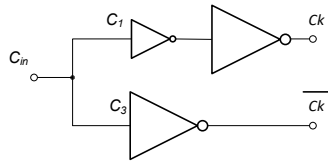
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Generating Complementary Clocks

- Inverter fork

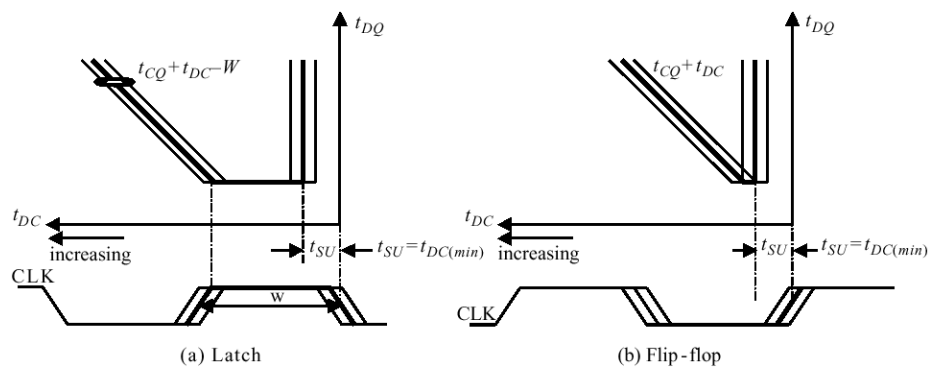


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Latch vs. Flip-Flop



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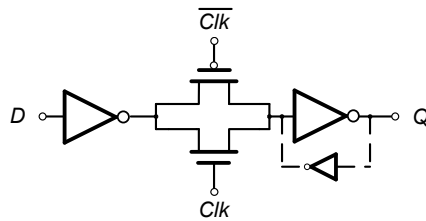
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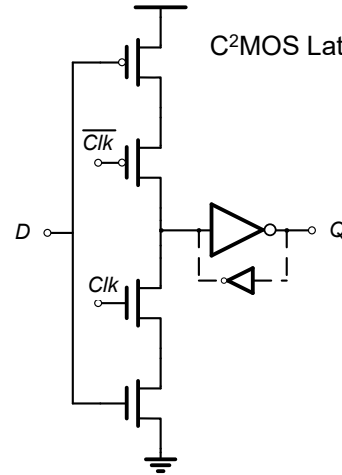
Latches

Transmission-Gate Latch



Usually without contention

C²MOS Latch

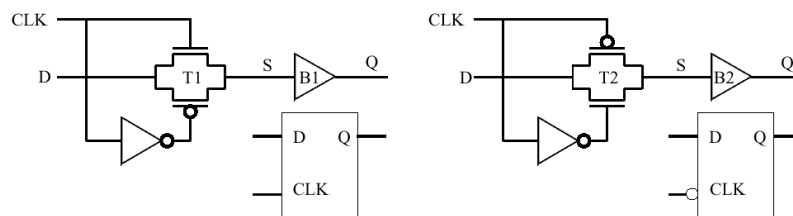


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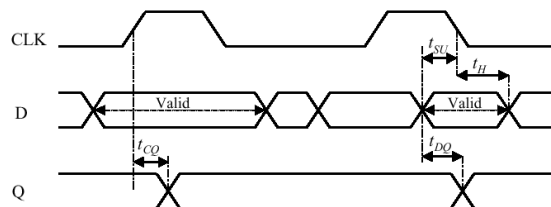
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Latches



(a) The transparent high latch (THL)

(b) The transparent low latch (TLL)



(c) Timing waveforms for the THL

Courtesy of IEEE Press, New York. © 2000

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Announcements

- Quiz 1 next Tuesday, in lecture
- Lab 5 due this week
- Midterm reports due next week
 - 4 pages, conference format

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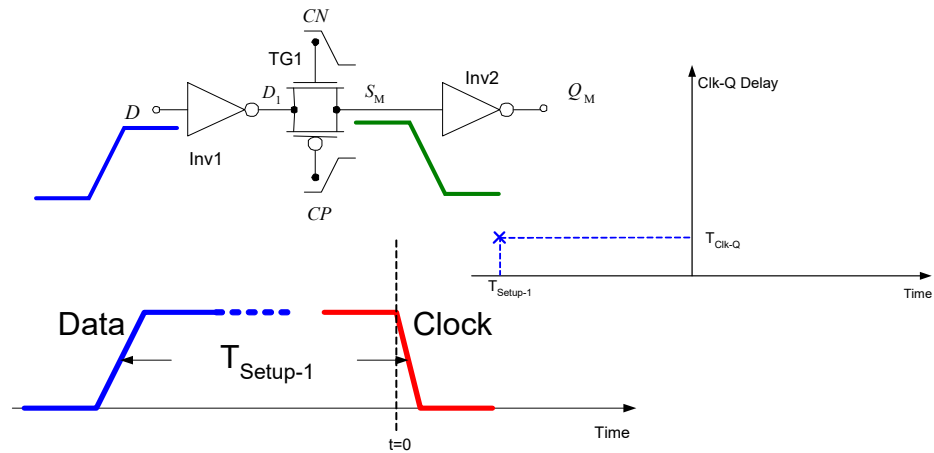
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Design for Performance

Delay, Setup, Hold

Setup-Hold Time Illustrations

Circuit before clock arrival (Setup-1 case)



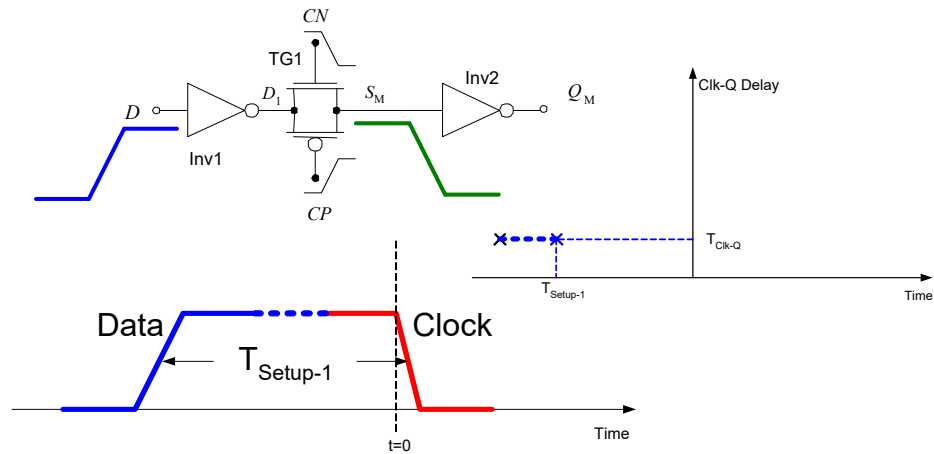
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Setup-Hold Time Illustrations

Circuit before clock arrival (Setup-1 case)



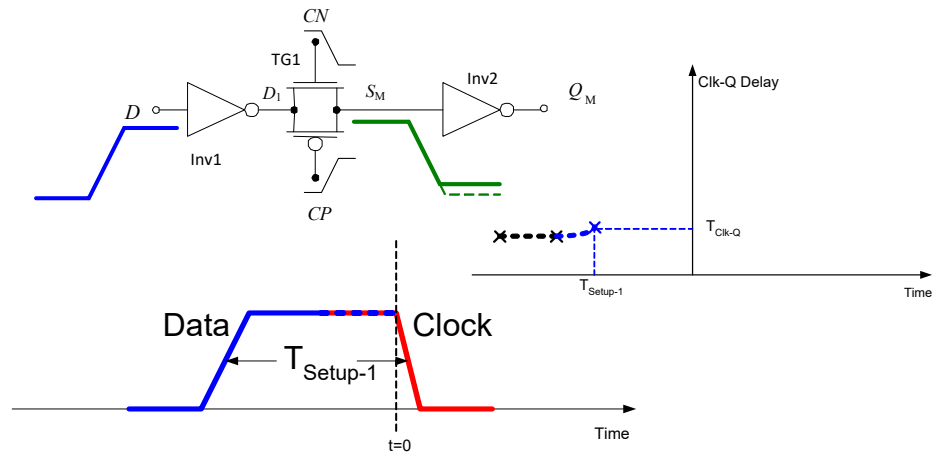
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Setup-Hold Time Illustrations

Circuit before clock arrival (Setup-1 case)



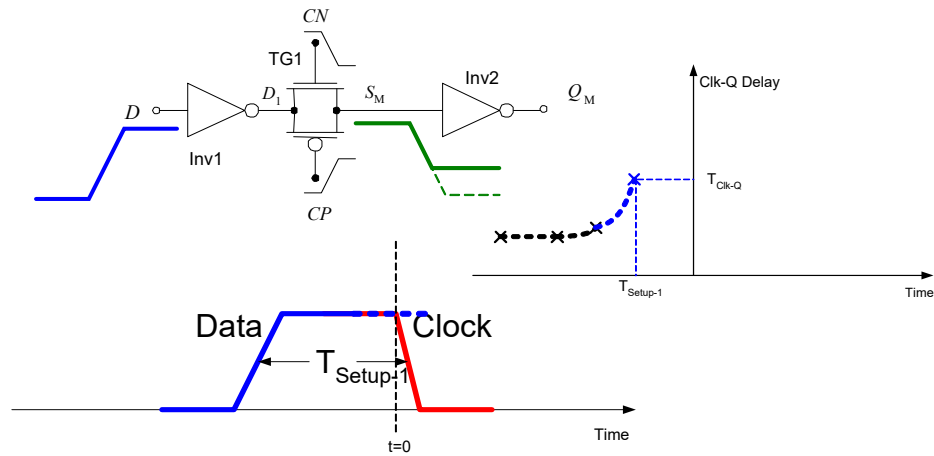
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Setup-Hold Time Illustrations

Circuit before clock arrival (Setup-1 case)



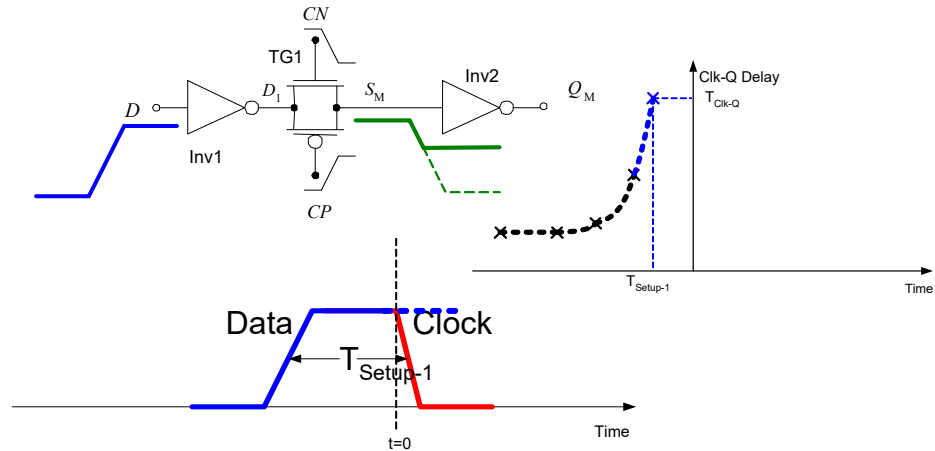
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Setup-Hold Time Illustrations

Circuit before clock arrival (Setup-1 case)



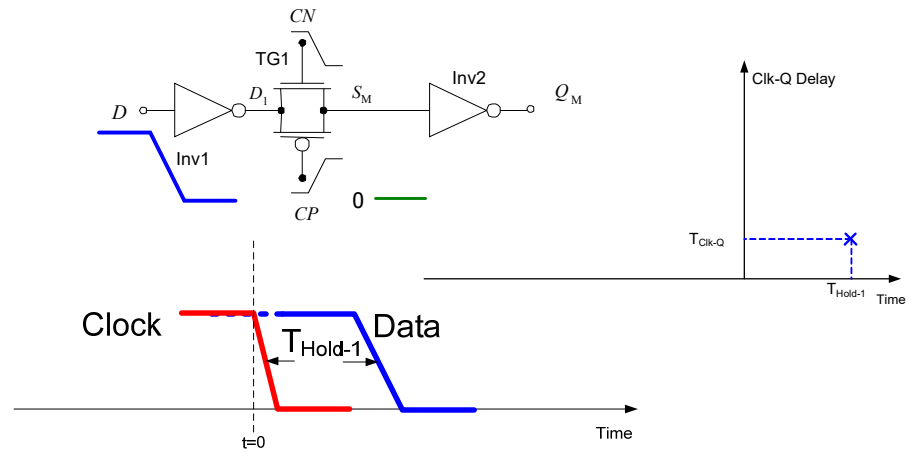
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Setup-Hold Time Illustrations

Hold-1 case



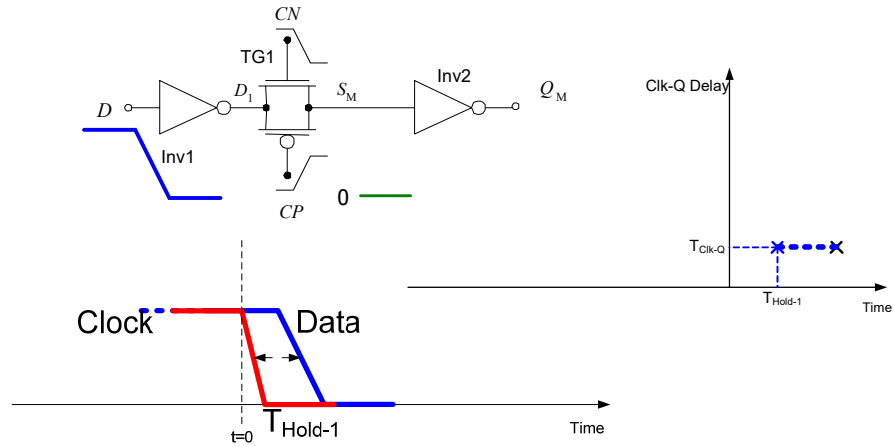
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Setup-Hold Time Illustrations

Hold-1 case



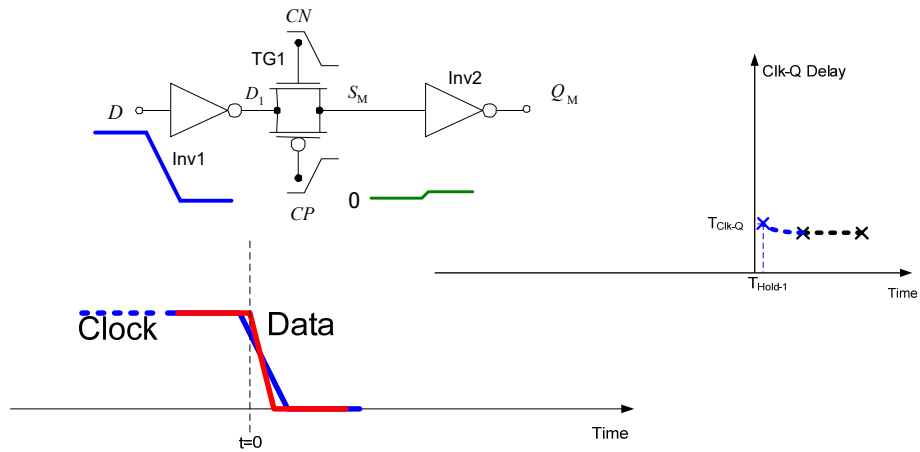
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Setup-Hold Time Illustrations

Hold-1 case



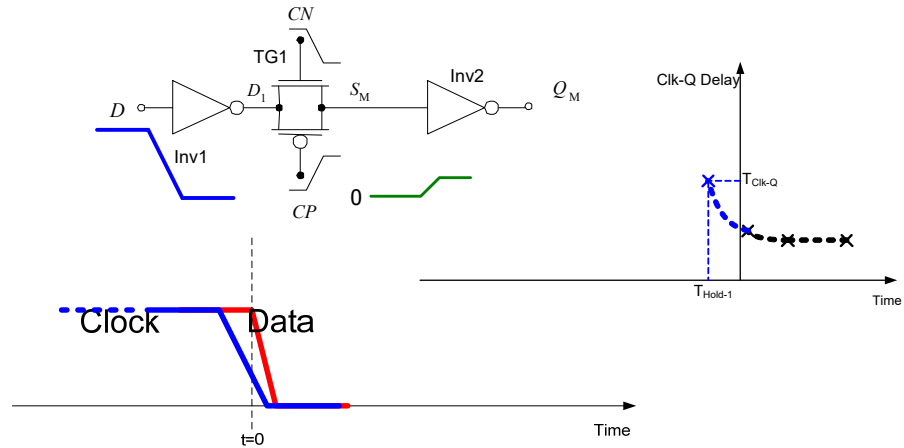
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Setup-Hold Time Illustrations

Hold-1 case



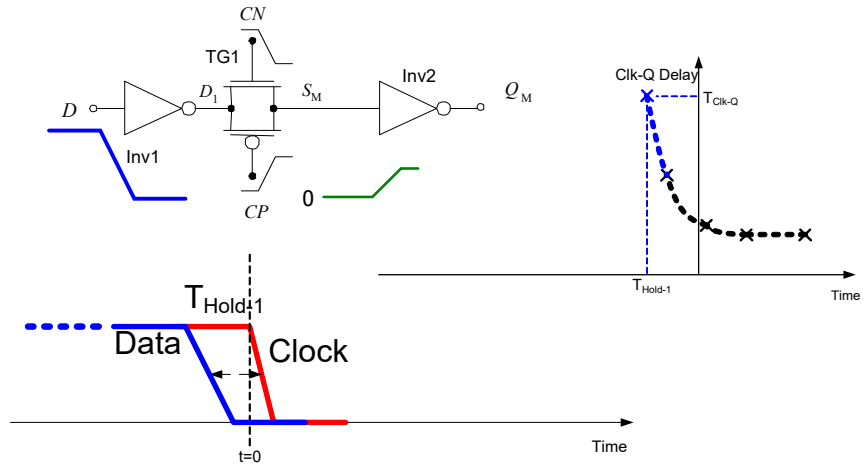
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Setup-Hold Time Illustrations

Hold-1 case

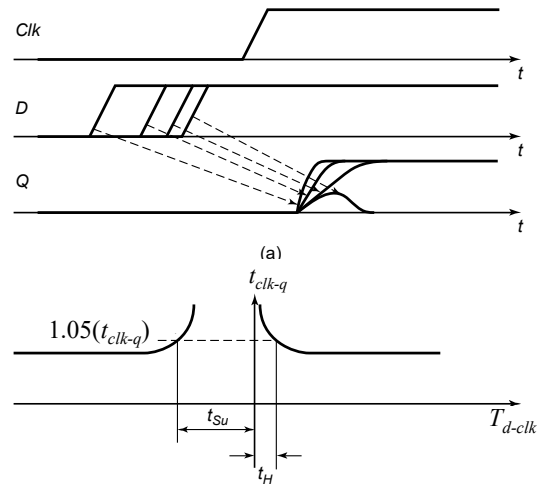


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More Precise Setup Time

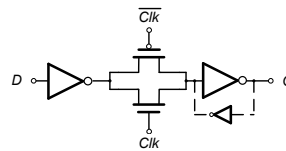


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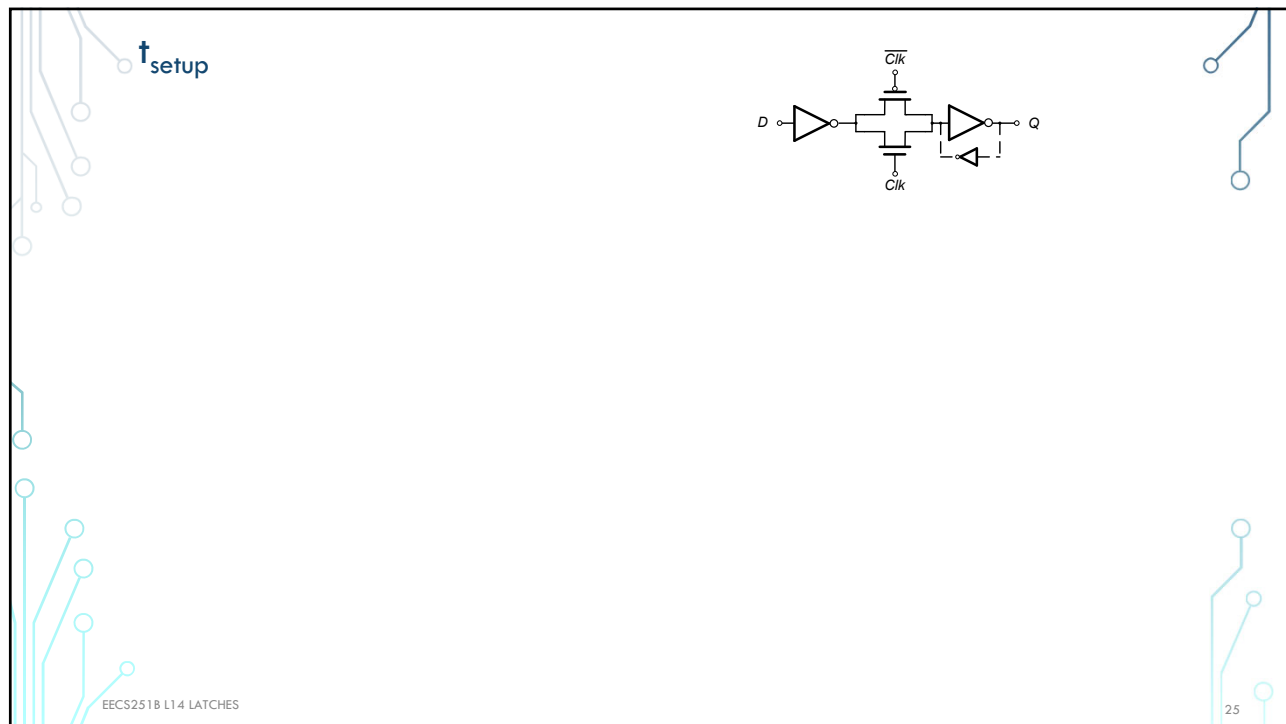
Latch t_{D-Q} and t_{Clk-Q}



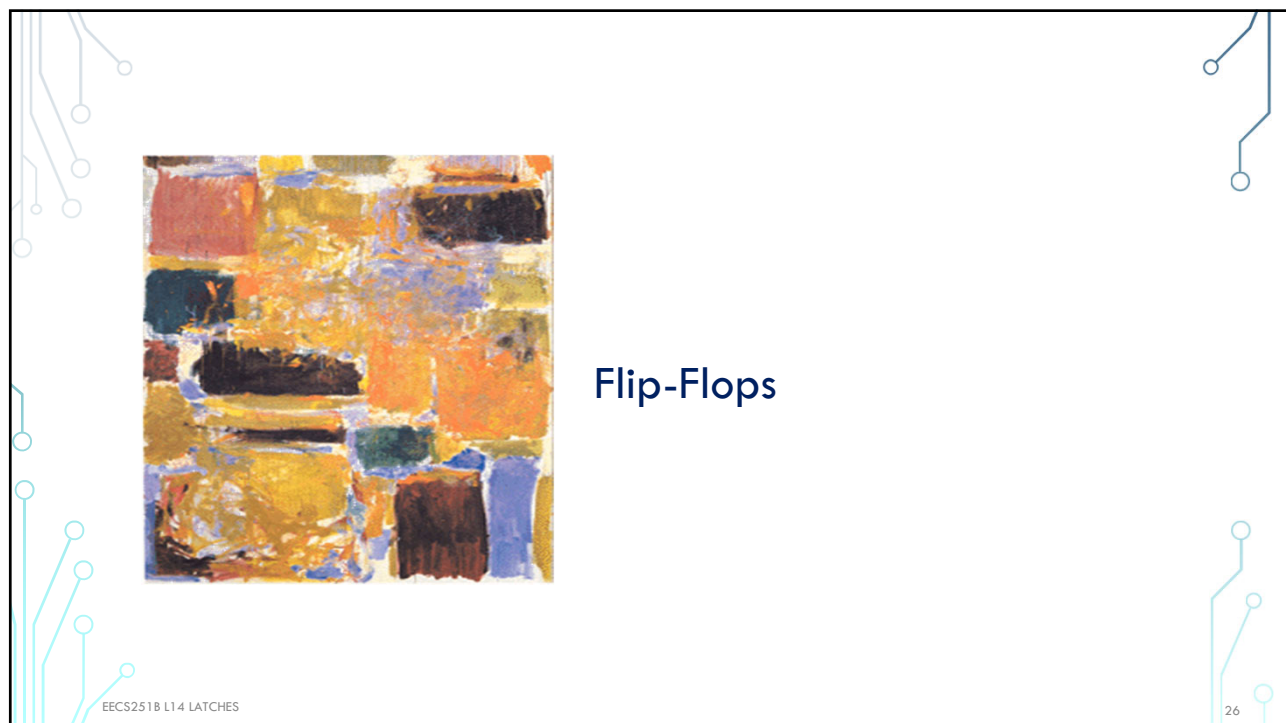
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Key Point

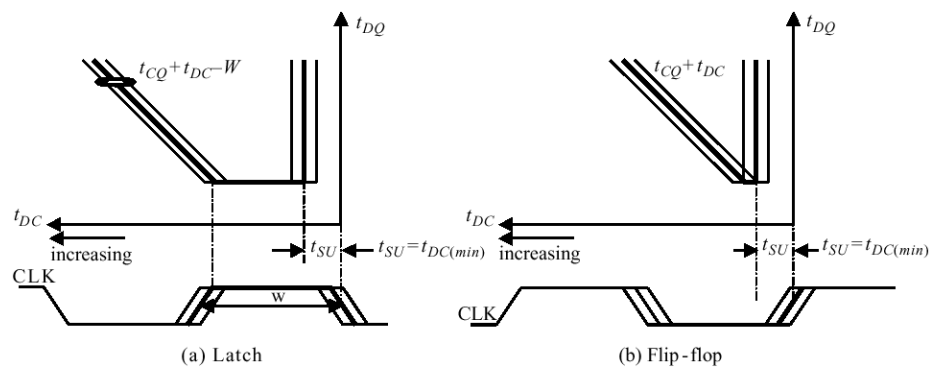
- Two ways to design a flip-flop
 - Latch pair (large majority)
 - Pulsed latch

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Latch vs. Flip-Flop



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Flip-Flops

- Performance metrics
- Delay metrics
 - Insertion delay
 - Inherent race immunity
 - 'Softness' (Clock skew absorption)
 - Inclusion of logic
 - Small (+constant) clock load
- Power/Energy Metrics
 - Power/energy
- Design robustness
 - Noise immunity

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Scan Test

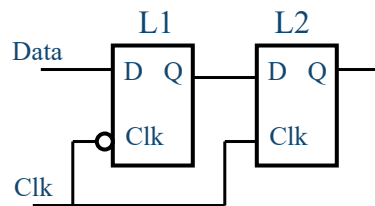
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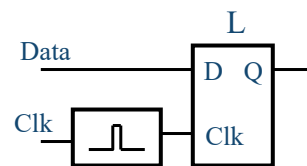
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Types of Flip-Flops

Latch Pair



Pulse-Triggered Latch

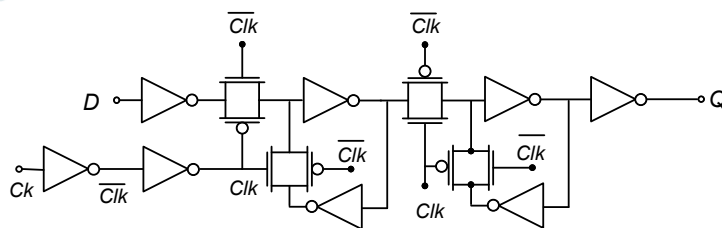


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Flip-Flop (Latch Pair) Clk-Q, setup, hold



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Flip-Flop Timing Characterization

- Combinational logic delay is a function of output load and input slope
- Sequential timing (flip-flop):
 - $t_{\text{clk-q}}$ is function of output load and clock rise time
 - $t_{\text{Su}}, t_{\text{H}}$ are functions of D and Clk rise/fall times

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Pulse-Triggered Latches

- First stage is a pulse generator
 - generates a pulse (glitch) on a rising edge of the clock
- Second stage is a latch
 - captures the pulse generated in the first stage
- Pulse generation results in a negative setup time
- Frequently exhibit a soft edge property
- Note: power is always consumed in the pulse generator
 - Often shared by a group (register)

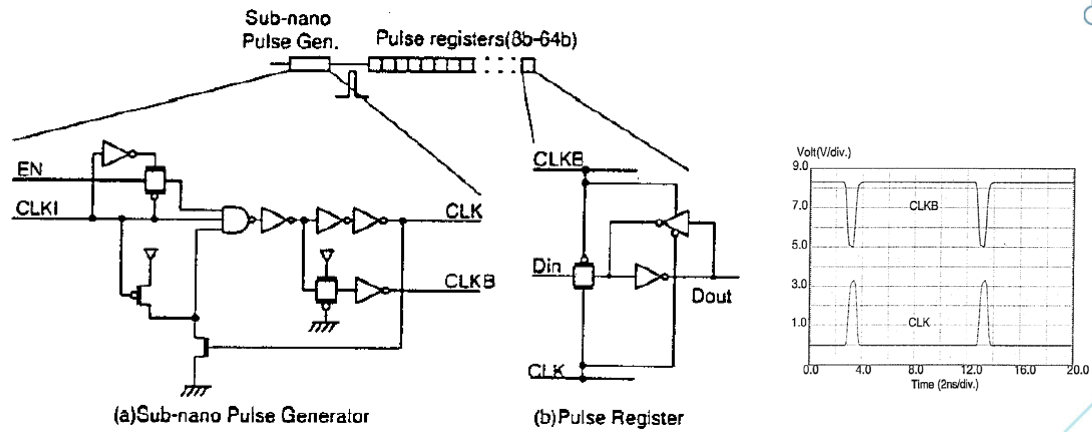
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Pulsed Latch

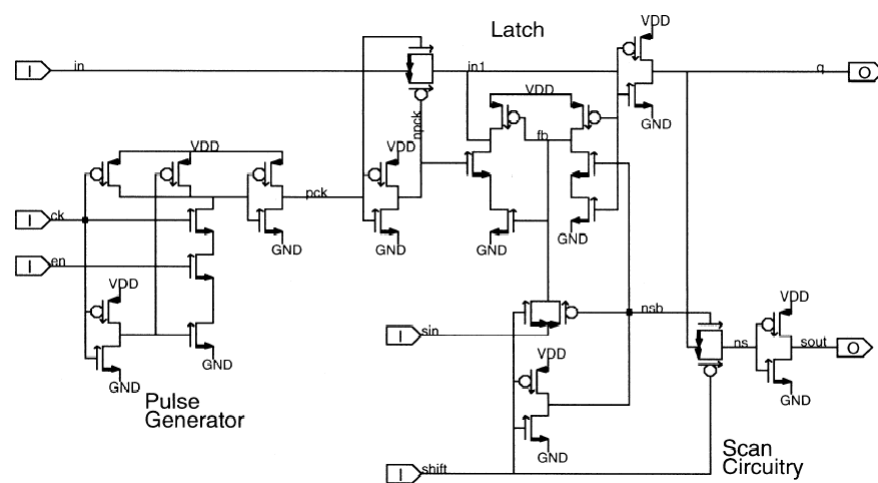
Simple pulsed latch



Kozu, ISSCC'96

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Intel/HP Itanium 2

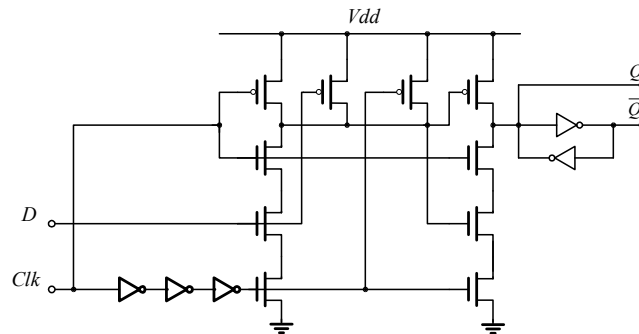


Naffziger, ISSCC'02

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Pulsed Latches

Hybrid Latch Flip-Flop, AMD K-6
Partovi, ISSCC'96



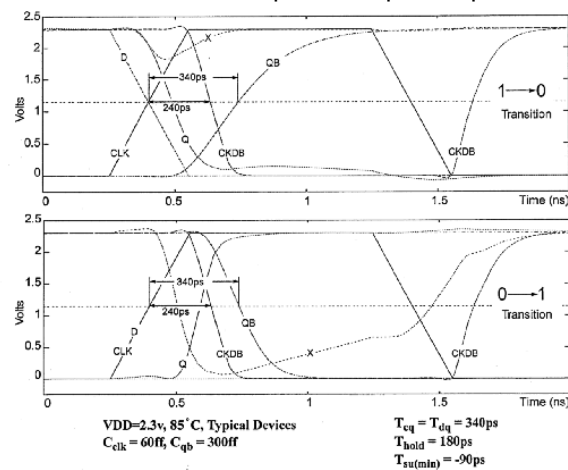
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HLFF Operation

1-0 and 0-1 transitions at the input with 0ps setup time



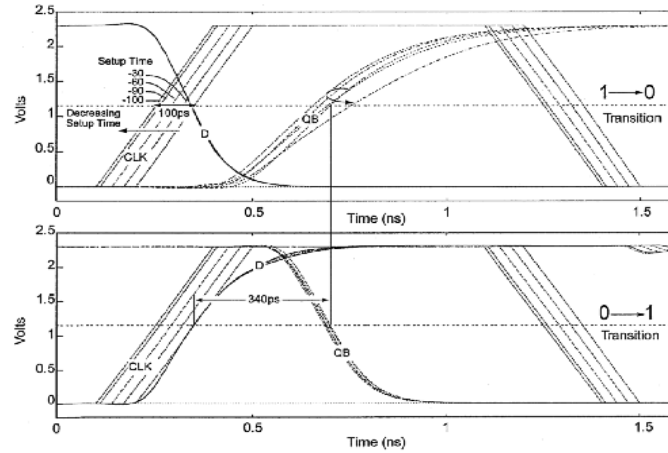
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Hybrid Latch Flip-Flop

Skew absorption



Partovi et al, ISSCC'96

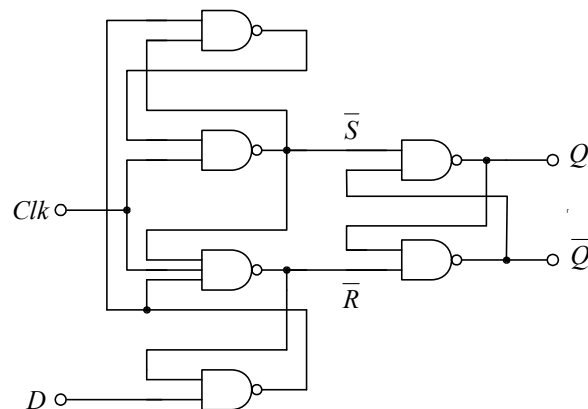
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Pulsed Latches

7474, from mid-1960's



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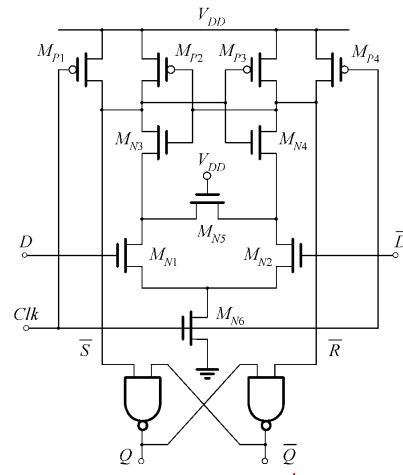
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Pulsed Latches

Sense-amplifier-based flip-flop, Matsui 1992.
DEC Alpha 21264, StrongARM 110

First stage is a sense amplifier, precharged to high, when $Clk = 0$
After rising edge of the clock sense amplifier generates the pulse on S or R
The pulse is captured in S-R latch
Cross-coupled NAND has different propagation delays of rising and falling edges

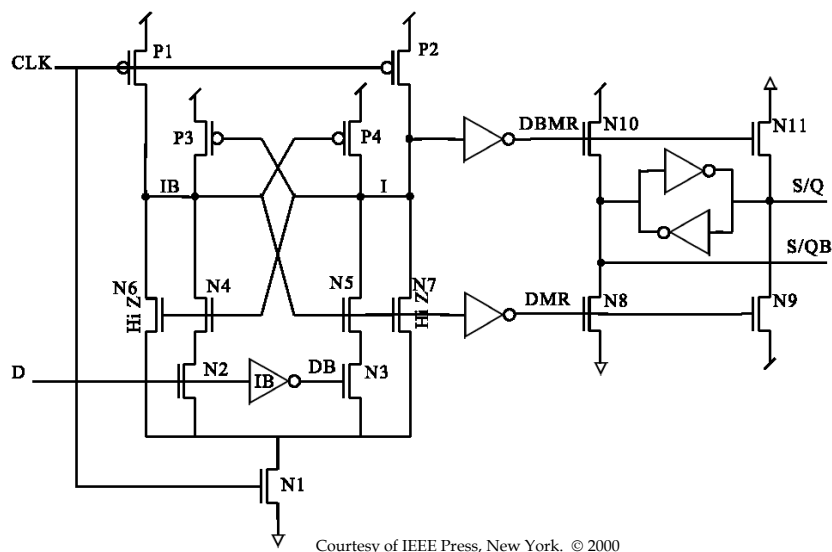


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Sense Amplifier-Based Flip-Flop

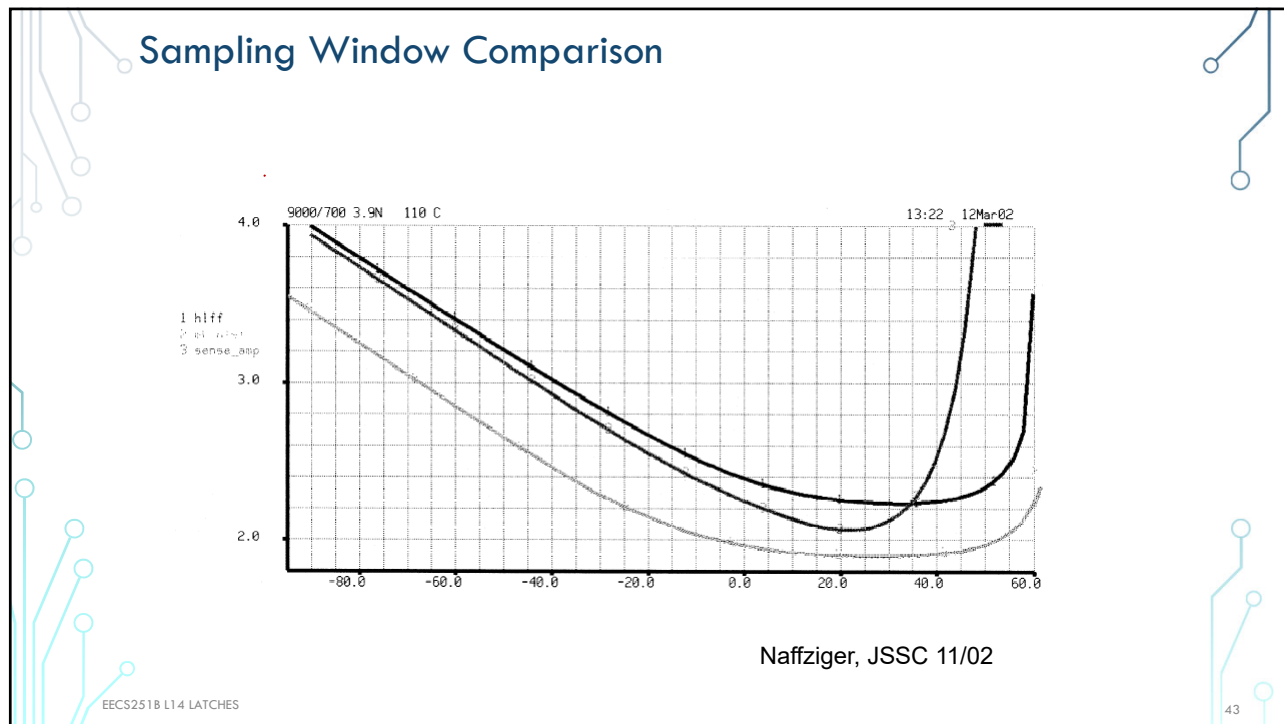


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Summary

- Logical effort can be used to analyze latch timing
 - Clk-Q, setup, hold
- Flip-flops:
 - Latch pairs
 - Pulse triggered

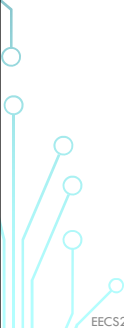

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Next Lecture

- Variability



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